SN74LVC02A QUADRUPLE 2-INPUT POSITIVE-NOR GATE

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- EPIC[™] (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 2 V at V_{CC} = 3.3 V, T_A = 25°C
- Inputs Accept Voltages to 5.5 V
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages

D, DB, OR PW PACKAGE (TOP VIEW) 14 V_{CC} 1Y 1A 13 4Y 1В П 12**∏** 4B 2Y [11 1 4A 2A 10 3Y 2B **∏** 9 3B 8∏ 3А GND I

description

This quadruple 2-input positive-NOR gate is designed for 2.7-V to 3.6-V V_{CC} operation.

The SN74LVC02A performs the Boolean function $Y = \overline{A + B}$ or $Y = \overline{A} \bullet \overline{B}$ in positive logic.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

The SN74LVC02A is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each gate)

INP	UTS	OUTPUT
Α	В	Y
Н	Х	L
Х	Н	L
L	L	Н



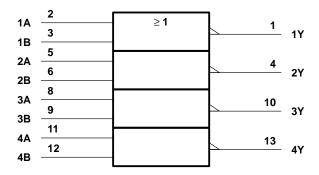
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram, each gate (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}	0.5 V to 6.5 V
Input voltage range, V _I (see Note 1)	
Output voltage range, V _O (see Notes 1 and 2)	\dots -0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3): D package	127°C/W
DB package	158°C/W
PW package	170°C/W
Storage temperature range, T _{stq}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - 2. The value of V_{CC} is provided in the recommended operating conditions table.
 - 3. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.



recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
\/	Supply voltage Operating Data reter	Operating	2	3.6	V
Vcc		Data retention only	1.5		V
VIH	High-level input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		V
VIL	Low-level input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8	V
٧ _I	Input voltage		0	5.5	V
٧o	Output voltage		0	VCC	V
lou.	High-level output current	$V_{CC} = 2.7 \text{ V}$		-12	mA
ЮН	riigh-level output current	V _{CC} = 3 V		-24	ША
lo.	Low-level output current	$V_{CC} = 2.7 \text{ V}$		12	mΑ
lOL	Low-level output current	V _{CC} = 3 V		24	ША
TA	Operating free-air temperature	·	-40	85	°C

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	v _{cc} †	MIN	TYP [†]	MAX	UNIT
	$I_{OH} = -100 \mu\text{A}$	2.7 V to 3.6 V	V _{CC} -0.2			
\/a	10 10.m4	2.7 V	2.2			V
VOH	I _{OH} = −12 mA	3 V	2.4			V
	I _{OH} = -24 mA	3 V	2.2			
	$I_{OL} = 100 \mu\text{A}$	2.7 V to 3.6 V			0.2	
VOL	I _{OL} = 12 mA	2.7 V			0.4	V
	I _{OL} = 24 mA	3 V			0.55	
lį	V _I = 5.5 V or GND	3.6 V			±5	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	3.6 V			10	μΑ
ΔlCC	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	2.7 V to 3.6 V			500	μΑ
Ci	$V_I = V_{CC}$ or GND	3.3 V		5	·	pF

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO (OUTPUT)	V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		UNIT	
		(001701)	MIN	MAX	MIN	MAX	
^t pd	A or B	Υ	1	4.4		5.4	ns
t _{sk(o)} ‡				1			ns

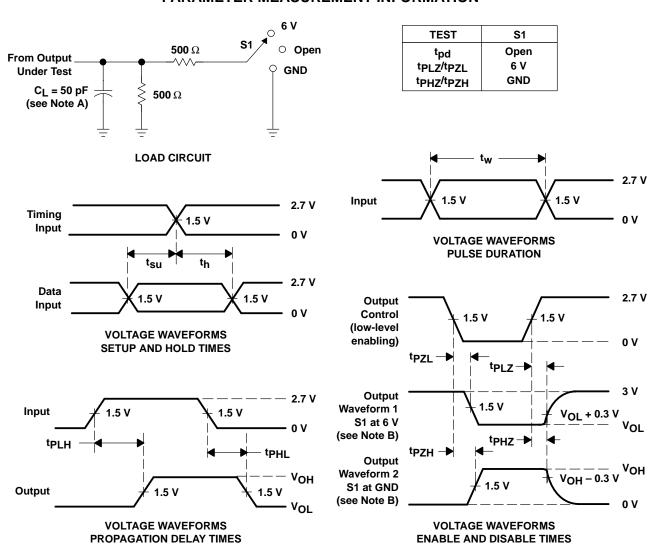
^{\$\}frac{1}{2}\$ Skew between any two outputs of the same package switching in the same direction. This parameter is warranted but not production tested.

operating characteristics, V_{CC} = 3.3 V, T_A = 25°C

	PARAMETER		TEST CO	TYP	UNIT	
ſ	C _{pd}	Power dissipation capacitance per gate	C _L = 50 pF,	f = 10 MHz	9.5	pF



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{O} = 50 Ω , $t_{f} \leq$ 2.5 ns, $t_{f} \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzI and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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